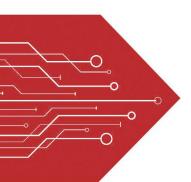
MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data sheet





1. BASE

SOT - 23

3. COLLECTOR

2. EMITTER

TRANSISTOR (NPN)

FEATURES

- High Collector Current.
- Complementary to S9012-MS
- Excellent h_{FE} Linearity.

MARKING: J3

MAXIMUM RATINGS (T_a=25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
V _{CBO}	Collector-Base Voltage	40	V
V _{CEO}	Collector-Emitter Voltage	25	V
V _{EBO}	Emitter-Base Voltage	5	V
Ic	Collector Current	500	mA
Pc	Collector Power Dissipation	300	mW
R _{OJA}	Thermal Resistance From Junction To Ambient	416	°C/W
T _J ,T _{stg}	Operation Junction and Storage Temperature Range	-55~+150	°C

ELECTRICAL CHARACTERISTICS (T_a=25°C unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V _{(BR)CBO}	I _C =0.1mA, I _E =0	40			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C =1mA, I _B =0	25			V
Emitter-base breakdown voltage	V _{(BR)EBO}	I _E =0.1mA, I _C =0	5			V
Collector cut-off current	ctor cut-off current I _{CBO} V _{CB} =40V, I _E =0				0.1	uA
Collector cut-off current	I _{CEO}	V _{CE} =20V, I _B =0			0.1	uA
Emitter cut-off current	I _{EBO}	V _{EB} =5V, I _C =0			0.1	uA
DC ourrent sein	h _{FE(1)}	V _{CE} =1V, I _C =50mA	120		400	
DC current gain	h _{FE(2)}	V _{CE} =1V, I _C =500mA	40			
Collector-emitter saturation voltage	V _{CE(sat)}	I _C =500mA, I _B =50mA			0.6	V
Base-emitter saturation voltage	$V_{BE(sat)}$	I _C =500mA, I _B =50mA			1.2	V
Base-emitter voltage	V_{BE}	V _{CB} =1V,I _C =10mA,			0.7	V
Transition frequency	f _T	V _{CE} =6V,I _C =20mA, f=30MHz	150			MHz
Collector output capacitance	C _{ob}	V _{CB} =6V, I _E =0, f=1MHz			8	pF

CLASSIFICATION OF h_{FE(1)}

RANK	L	Н	J
RANGE	120-200	200-350	300-400

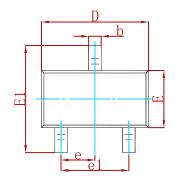


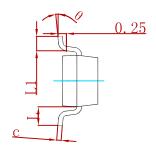


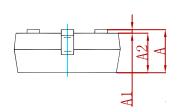




PACKAGE MECHANICAL DATA

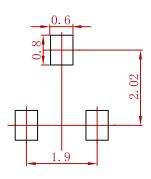






Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
Е	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.03	7 TYP	
e1	1.800	2.000	0.071	0.079	
Ĺ	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
S9013-MS	SOT-23	3000



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